		Application/Control No.	Applicant(s)/Patent Under Reexamination
Notice of References Cited		10/772,805	KEENAN, MICHAEL R.
		Examiner	Art Unit	Page 1 of 1

		Examiner	Art Unit	Page 1 of 1
		Farras Abdelnour	2624	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0146160	10-2002	Parker et al.	382/131
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Rapid analysis of Raman image data using two-way multivariate curve resolution," J.J. Andrew and T.M. Hancewicz, Applied Spectroscopy, Vol. 52, Number 6, 1998
	V	"Algorithms for constrained linear unmixing with application to the hyperspectral analysis of fluorophore mixtures," M.R. Keenan, J.A. Timlin, M.H. Van Benthem, and D.M. Haaland , Proc. SPIE 4816, 193-202 (2002)
	W	F. Vogt and M. Tacke, Fast principal component analysis of large data sets, Chemometrics and Intelligent Laboratory Systems, Volume 59, Issues 1-2, 28 November 2001, Pages 1-18.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.